

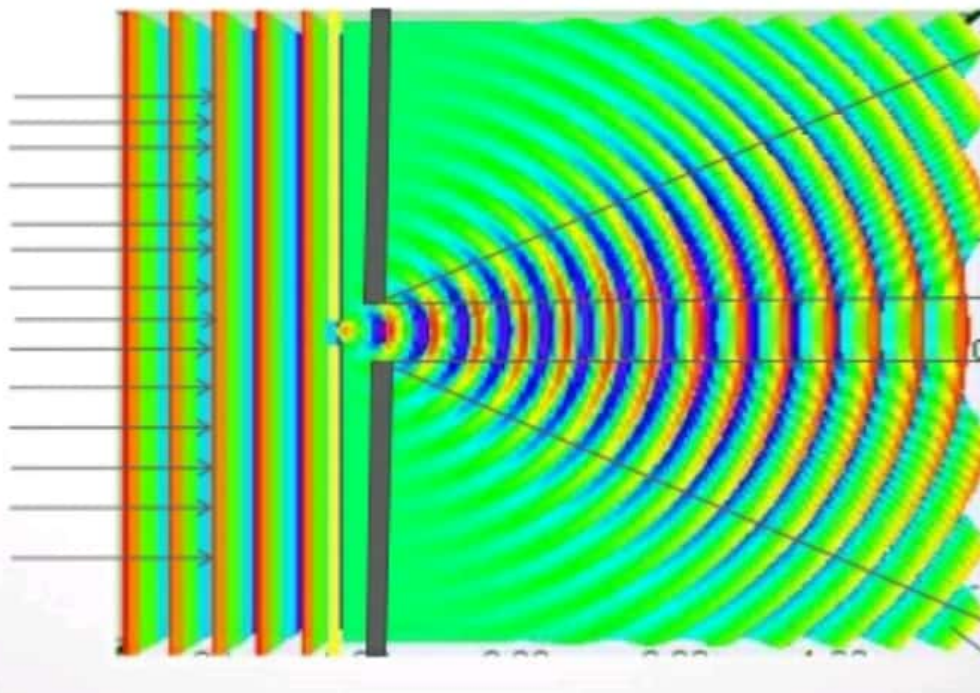
ELECTRON DIFFRACTION

CONTAIN

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ELECTRON DIFFRACTION

1) **INTRODUCTION :- a) DIFFRACTION:-** The process by which a beam of light or other system of wave spread out as a result of passing through a narrow aperture or across an edge.



ELECTRON DIFFRACTION

- DE BROGLIE to conclude that Moving electron possess dual nature

1) wave

2) Partical

$$\lambda = h/p$$

$$\lambda = h/mv \dots\dots\dots(1)$$

we know that

$$K.E. = 1/2(mv^2) \dots\dots\dots(2)$$

$$\& K.E. = Ve \dots\dots\dots(3)$$

By equation (2) & (3)

$$1/2(mv^2) = Ve$$

$$mv^2 = 2Ve$$

$$v = 2Ve/m$$

$$v = (2Ve/m)^{1/2} \dots\dots\dots(4)$$

Put value of v in equation (1)

$$\lambda = \frac{h}{m \left(\frac{2Ve}{m} \right)^{1/2}}$$

$$\lambda = \frac{h}{(2Ve.m)^{1/2}}$$

Put standard value of h,m,e & sol

$$\lambda = 12.25 / \sqrt{V} \text{ \AA}$$

where	
$\lambda =$	wave length
$h =$	Plank's constant
$m =$	Mass of electron
$v =$	velocity
$V =$	Potential difference
$e =$	Charge on electron
Standard	value
$h =$	6.602×10^{-34} JS
$m =$	9.110×10^{-31} Kg
$e =$	1.602×10^{-19} C

ELECTRON DIFFRACTION

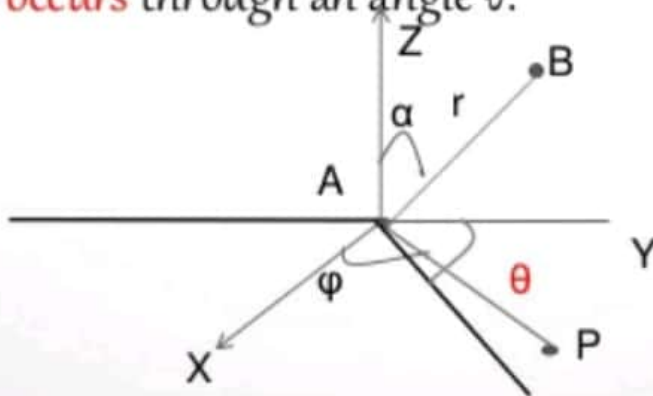
• 2) PRINCIPLE:-

- Electron can be accelerated to precisely controlled energy by applying a known potential difference.
- when **accelerated** through **10 keV** they acquire wave length **12pm** which makes then **suitable** for molecule diffraction.
- Electron diffraction study generally utilized with **energies** of the **order** of **40 keV**.
- **Since** electron are charged they are scattered strongly by their interaction with electron and nuclei of atom of the sample.
- **Hence** they cannot be used for studying molecule in gaseous state held on surface and in thin films. (the application to surface which is called **LOW ENERGY ELECTRON DIFFRACTION** is a major use of the technique.)

ELECTRON DIFFRACTION

• **3) SCATTERING INTENSITY & SCATTERING ANGLE:-**

- Consider diatomic molecule AB to study electron diffraction theory. The atom A lies at the origin and B at a distance r away
- The orientation of molecule AB is specified by angle α and ϕ .
- The incident electron beam enters parallel to Y-axis and diffraction **occurs** through an angle θ .

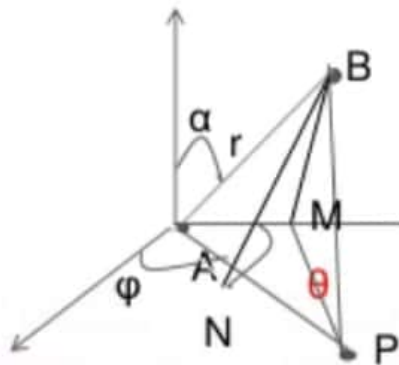


ELECTRON DIFFRACTION



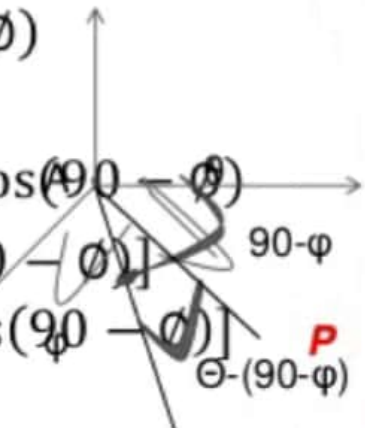
- The interference between the wave scattered A and B depends on the difference between the length of the paths the traverse .
- Draw from B a perpendicular BN on to diffraction direction and a perpendicular BM on to the undiffracted direction to calculate the path difference δ .
- when M and N are in phase the path difference is

$$\delta = AN - AM$$



ELECTRON DIFFRACTION

- PM is perpendicular to AY and PN is perpendicular to the diffracted beam.
- $\delta = AN - AM$
- $\delta = AP \cos(\theta + \phi - 90) - AP \cos(90 - \phi)$
- $\therefore AP = r \sin \alpha$
- $\delta = r \sin \alpha \cos(\theta + \phi - 90) - r \sin \alpha \cos(90 - \phi)$
- $\delta = r \sin \alpha [\cos(\theta + \phi - 90) - \cos(90 - \phi)]$
- $\delta = r \sin \alpha [\cos - \{90 - (\theta + \phi)\} - \cos(90 - \phi)]$
- **Formula** [$\cos - \theta = \cos \theta$]
- $\delta = r \sin \alpha [\cos(90 - \theta + \phi) - \cos(90 - \phi)]$
- **Formula** [$\cos(90 - \theta) = \sin \theta$]
- $\delta = r \sin \alpha [\sin(\theta + \phi) - \sin \phi]$
- $\sin C - \sin D = 2 \left[\cos \frac{C+D}{2} \times \sin \frac{C-D}{2} \right]$
- $\delta = r \sin \alpha \cdot 2 \left[\cos \frac{\theta + \phi + \phi}{2} \times \sin \frac{(\theta + \phi - \phi)}{2} \right]$



ELECTRON DIFFRACTION

- The difference in phase between two scattered waves is $(2\pi/\lambda)\delta$.
- Assuming the atoms A & B identical the resultant amplitude at P is
- $A = A_0 + A_0 e^{2\pi i \delta / \lambda}$
- $A = A_0 (1 + e^{2\pi i \delta / \lambda})$
- where A_0 = atoms form factor for electron scattering (depends on the nuclear charge of the atom.)
- The intensity of radiation is proportional to square of the amplitude .
- $I = A^2$
- $I = A \cdot \bar{A}$
- $I = A_0 (1 + e^{2\pi i \delta / \lambda}) \cdot A_0 (1 + e^{-2\pi i \delta / \lambda})$
- $I = A_0^2 (1 + e^{2\pi i \delta / \lambda}) (1 + e^{-2\pi i \delta / \lambda})$
- Formula $(1 + e^{i\theta})(1 + e^{-i\theta}) = 2(1 + \cos \theta)$

ELECTRON DIFFRACTION

- The differential element of solid is $\sin \alpha d\alpha d\phi$ and the total solid angle is 4π
- *thus the average scattering intensity is given by*
- $I_{av} \sim \frac{4A^2}{4\pi}$
 $\int_0^{2\pi} \int_0^\pi \cos^2[2r\pi/\lambda \sin \theta / 2 \sin \alpha \cos(\phi +$

ELECTRON DIFFRACTION

4) WIERL EQUATION:-

- when the molecule consist of a number of atom, we sum over the contribution from all pair and find that **total intensity** has an angular variation.
- Given by equation:

$$I(\theta) = \sum_{ij} f_i f_j \sin s R$$

where $s = 4 \frac{\pi}{\lambda} \cdot \sin \frac{\theta}{2}$

where	
f=	Electron scattering factor
λ =	wave length
θ =	Scattering angle

ELECTRON DIFFRACTION

• 5) APPLICATION OF ELECTRON DIFFRACTION :-

- i. *Electron diffraction studies is useful for evaluating **bond length and bond angle** in simple gas phase molecule.*
- ii. *The **accuracy** of bond length obtained from electron diffraction studies is comparable to X-ray diffraction studies for simple gas phase molecules.*
- iii. *This shows that difficulties lie in the path of structure determination by electron diffraction .*
- iv. ***Many molecular structure** have been **determined** by this method.*

Bond length and bond angle in some compounds.

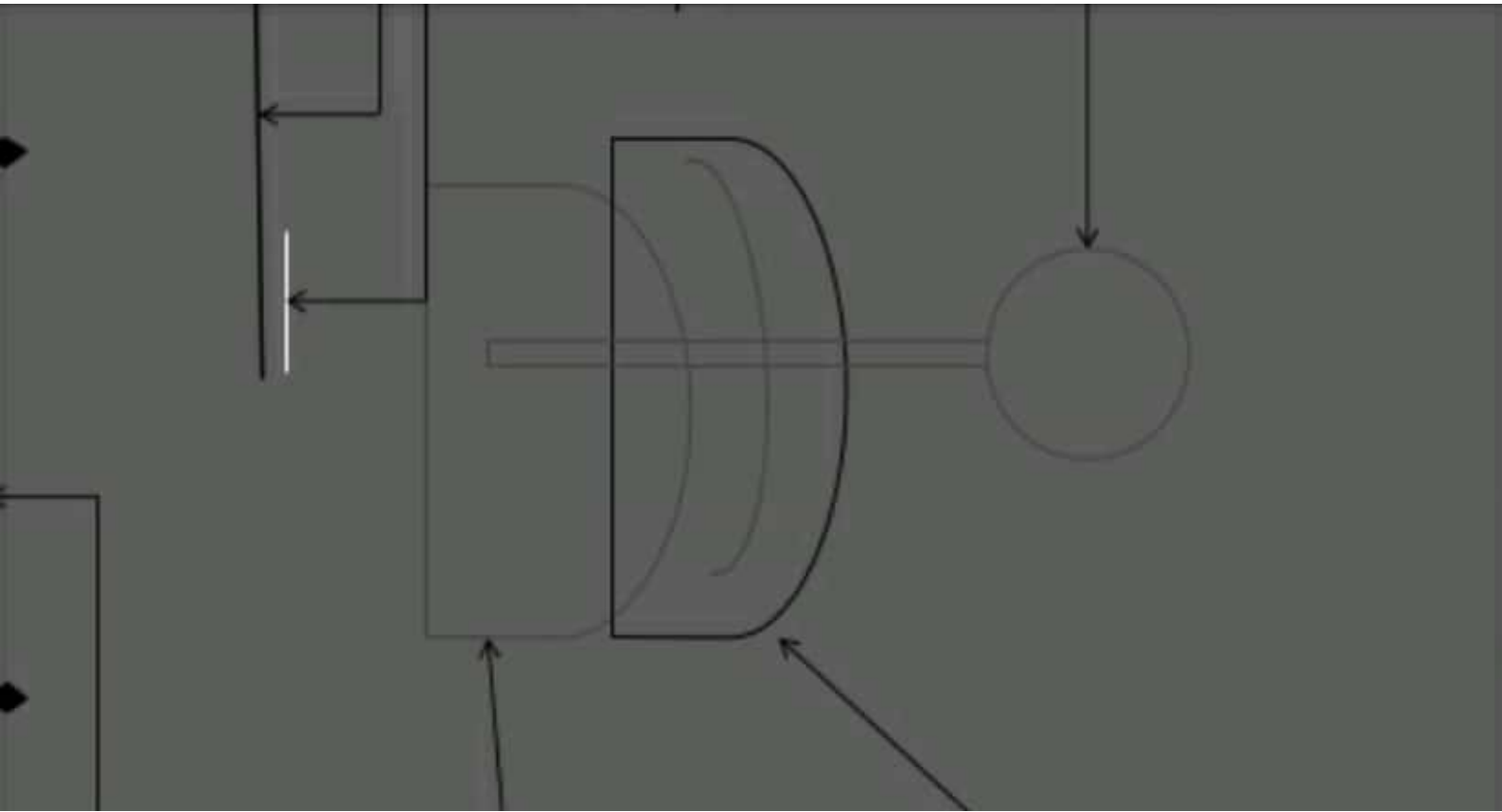
Compound	Bond	Bond length in pm	Geometry
CCl_4	Cl-Cl	285	Tetrahedral
GeCl_4	Ge-Cl	208	Tetrahedral
TiCl_4	Ti-Cl	218	Tetrahedral
SF_6	S-F	158	Octahedral

ELECTRON DIFFRACTION



1) **LOW ENERGY ELECTRON DIFFRACTION (LEED) & STRUCTURE OF SURFACES :-**

- **LEED is one of the most informative technique for determining the arrangement of atom close to the surface .**
- **LEED generally electron diffraction but the sample is now the surface of a solid.**
- **The use of low energy (10 to 200 eV) electrons corresponding to wave lengths in the range 100 to 400 pm .**
- **The experimental arrangement used for LEED consists of**
 - i. Sample container**
 - ii. Electron gun**
 - iii. Grids**
 - iv. & phosphor screen**



ELECTRON DIFFRACTION

- The LEED pattern portrays the two dimensional structure of surface.
- **Note:-**
 - At angles to a plane of atom. LEED pattern is **sharp** if surface is well ordered for long distances compared with the wave length of incident electron.*
 - ❖ **Generally** , sharp patterns are obtained for surfaces ordered to depths of **20 nm** or more .
 - ii. Diffuse LEED** pattern show the poorly ordered surface or presence of **impurities**.
 - iii. The pattern is *affected* by the presence of **terraces** , **steps and kinks** in a surface.**
 - iv. The sample can be obtained by cleaning a crystal at different**

ELECTRON DIFFRACTION

7) APPLICATIONS OF LEED :-

- *LEED is one of the most informative technique for Determining the **arrangement of atoms** close to the surface.*
- *LEED pattern may be used to assess the **defect density** .*